Title (en)

MEASURING SYSTEM FOR DETERMINING SCATTER PARAMETERS

Title (de)

MESSSYSTEM ZUM BESTIMMEN VON STREUPARAMETERN

Title (fr)

SYSTÈME DE MESURE POUR DÉTERMINER DES PARAMÈTRES DE DISPERSION

Publication

EP 2338063 A1 20110629 (DE)

Application

EP 09778771 A 20090929

Priority

• EP 2009007010 W 20090929
• DE 202008013982 U 20081020

Abstract (en)

[origin: CA2738717A1] The invention relates to a measuring system for determining scatter parameters of an electrical measurement object (40, 42, 44, 46, 48) on a substrate (38), having a measuring machine (10) having at least one measuring channel (18, 20, 22, 24) and at least one measuring probe (28) electrically connected to at least one measuring channel (18, 20, 22, 24) and designed for non-contacting or contacting connection to an electrical signal line (50) of the electrical measurement object (40, 42, 44, 46, 48) in the electronic circuit. According to the invention, a first positioning device (30) is provided for at least one measuring probe (28), wherein at least one sensor (34) detects a position of at least one measuring probe (28) and outputs a position signal.

IPC 8 full level

G01R 1/067 (2006.01); **G01R 27/28** (2006.01)

CPC (source: EP KR US)

G01R 1/067 (2013.01 - KR); **G01R 27/28** (2013.01 - EP KR US); **G01R 31/28** (2013.01 - KR)

Citation (search report)

See references of WO 2010046017A1

Citation (examination)

• US 4203064 A 19800513 - HASHIMOTO SUSUMU [JP], et al
• CHUN-PING CHEN ET AL: "Compact magnetic loop probe for microwave EM field-mapping and its applications in dielectric constant measurement", MICROWAVE CONFERENCE, 2007. EUROPEAN, IEEE, PI, 1 October 2007 (2007-10-01), pages 226 - 229, XP031191775, ISBN: 978-2-87487-001-9, DOI: 10.1109/EUMC.2007.4405167

Designated contracting state (EPC)

AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI LT LU LV MC MK MT NL NO PL PT RO SE SI SK SM TR

Designated extension state (EPC)

AL BA RS

DOCDB simple family (publication)

DE 202008013982 U1 20090108; CA 2738717 A1 20100429; CA 2738717 C 20140826; CN 102187233 A 20110914; CN 102187233 B 20140319; EP 2338063 A1 20110629; HK 1159252 A1 20120727; JP 2012506030 A 20120308; KR 101245382 B1 20130322; KR 20110070903 A 20110624; US 2011241712 A1 20111006; US 9116189 B2 20150825; WO 2010046017 A1 20100429

DOCDB simple family (application)

DE 202008013982 U 20081020; CA 2738717 A 20090929; CN 200980141732 A 20090929; EP 09778771 A 20090929; EP 2009007010 W 20090929; HK 11112858 A 20111128; JP 2011531375 A 20090929; KR 20117010844 A 20090929; US 200913122504 A 20090929